SLOVENSKI STANDARD
SIST EN 60749-5:2017

01-september-2017

Nadomešča:
SIST EN 60749-5:2004

Polprevodniški elementi - Mehanske in klimatske preskusne metode - 5. del: Preskus življenjske dobe v dinamičnem ravnotežju vlažnosti in pri ustaljeni temperaturi (IEC 60749-5:2017)

Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test (IEC 60749-5:2017)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 5: Lebensdauerprüfung bei konstanter Temperatur und Feuchte unter elektrischer Beanspruchung (IEC 60749-5:2017)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 5: Essai continu de durée de vie sous température et humidité avec polarisation (IEC 60749-5:2017)

Ta slovenski standard je istoveten z: **EN 60749-5:2017**

ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general

SIST EN 60749-5:2017 **en**

EUROPEAN STANDARD

NORME EUROPÉENNE

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Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test (IEC 60749-5:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

European foreword

The text of document 47/2367/FDIS, future edition 2 of IEC 60749-5, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60749-5:2017.

The following dates are fixed:

• latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2018-02-15
• latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2020-05-15

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Annex ZA
(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

Publication	Year	Title	EN/HD	Year
IEC 60749-4	-	Semiconductor devices - Mechanical and climatic test methods - Part 4: Damp heat, steady state, highly accelerated stress test (HAST)	EN 60749-4	-

IEC 60749-5

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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SEMICONDUCTOR DEVICES – MECHANICAL AND CLIMATIC TEST METHODS –

Part 5: Steady-state temperature humidity bias life test

FOREWORD

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International Standard IEC 60749-5 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2003. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) correction of an error in an equation;
b) inclusion of notes for guidance;
c) clarification of the applicability of test conditions.